

Effect of V_{DD} Noise on Phase Jitter

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Outline

- What is phase noise and timing jitter?
- Impulse Sensitivity Function (ISF)
- Relationship of ISF and phase noise
- Minimize phase noise in circuit design
- Estimation of ISF
- Measuring ISF in circuit
- Conclusions

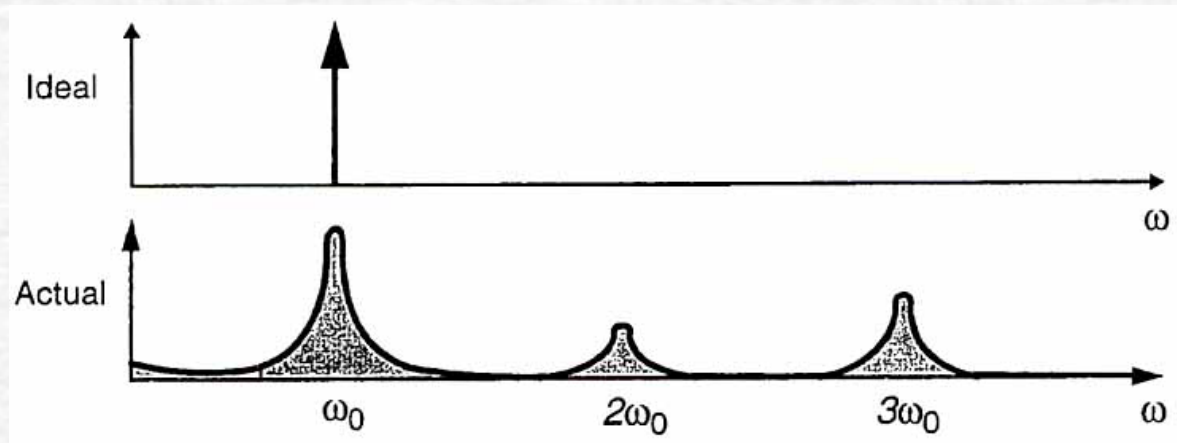
What is Phase Noise?

➤ Ideal oscillator output

- $V_{\text{out}}(t) = V_o \cos(\omega_o t + \phi_o)$

➤ Practical oscillator output

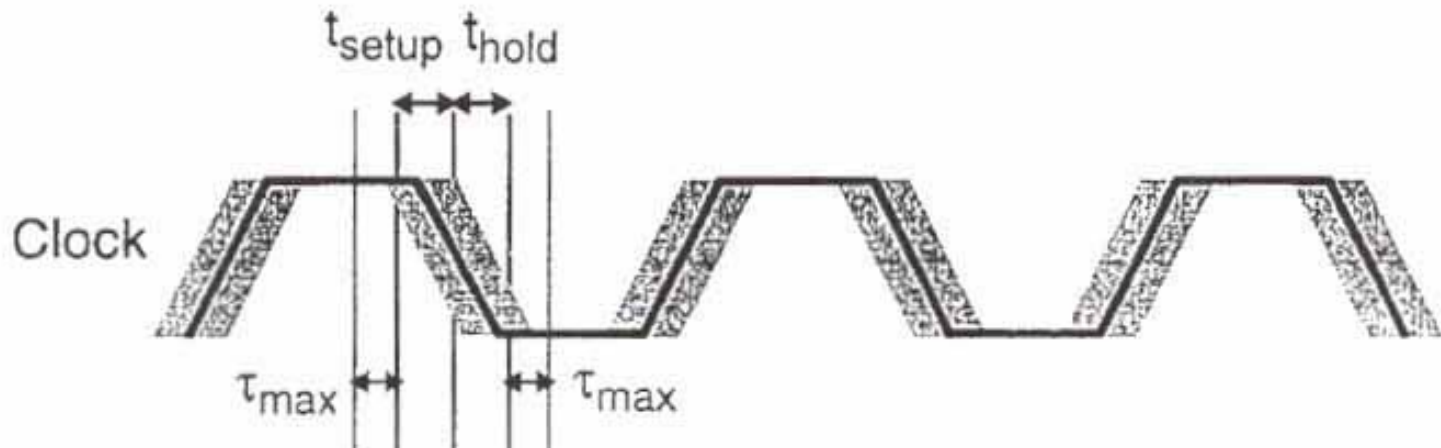
- $V_{\text{out}}(t) = V_o [1 + A(t)] \cos(\omega_o t + \phi(t))$



Timing Jitter

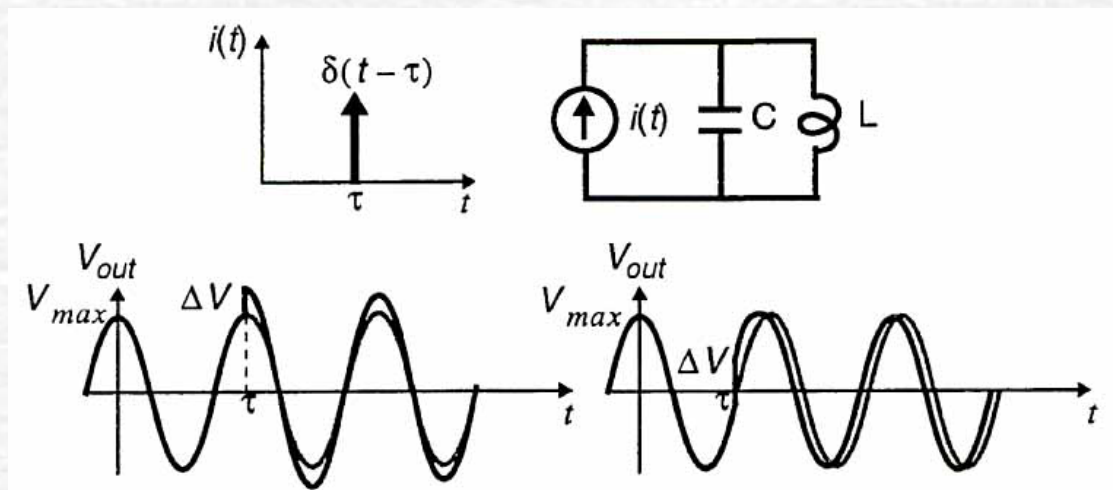
- Timing Jitter is time domain representation of phase noise
- Standard deviation of the phase uncertainty, δ_τ

$$\delta_\tau^2 = \frac{4}{\pi\omega_o} \int_0^\infty S_\phi(\omega) \sin^2\left(\frac{\omega\tau}{2}\right) d\omega$$



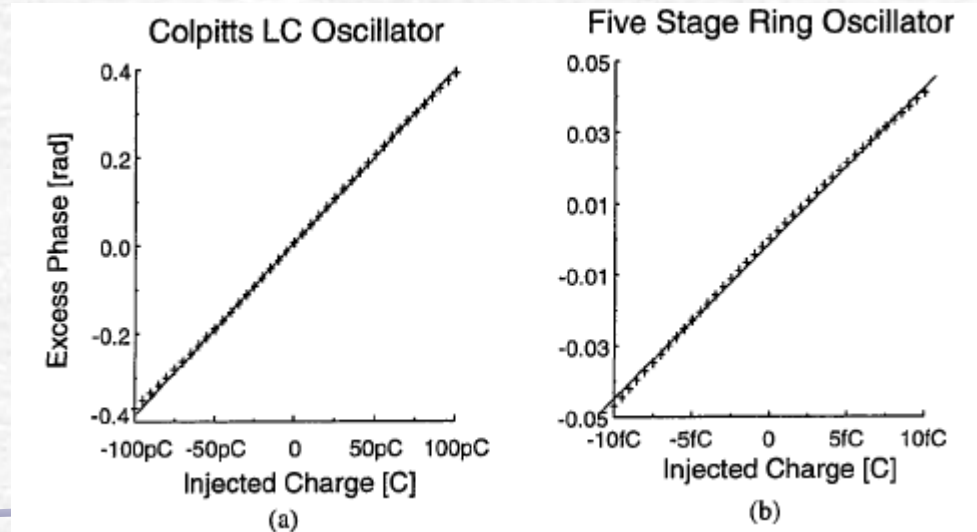
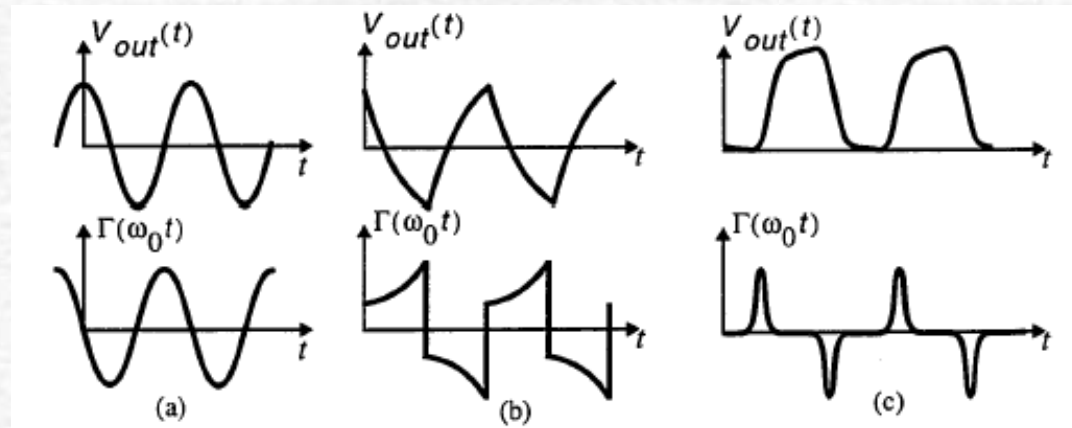
Impulse Sensitivity Function

- ISF = $\Gamma(\omega_o \tau)$
- Characterizes phase response of oscillator due to arbitrary noise source
- $\Delta\phi_{\text{impulse}} = \Gamma(\omega_o \tau) \Delta q / q_{\text{max}}, \Delta q \ll q_{\text{max}}$
- ISF is periodic with 2π

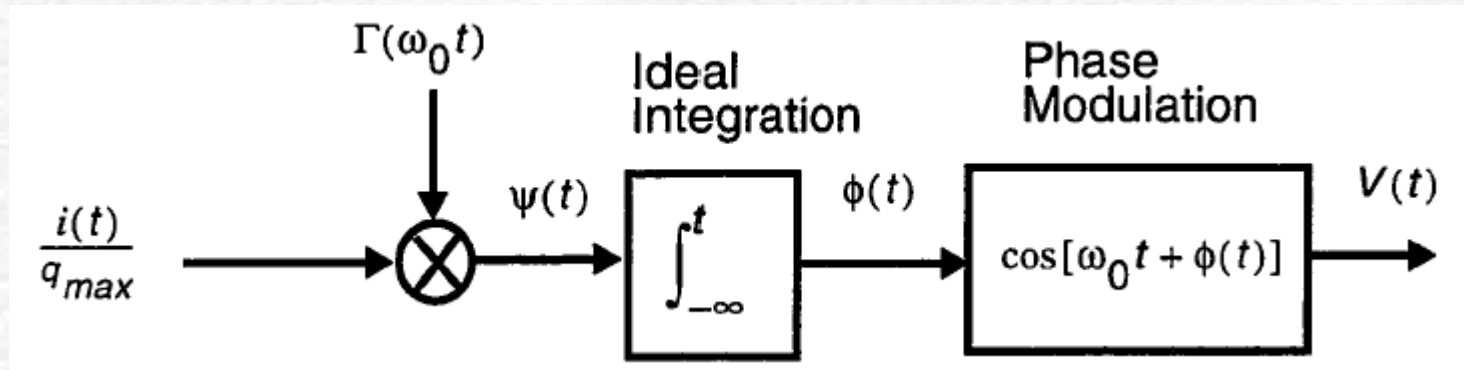


Result of ISF Simulations

- Different type of oscillations exhibit different ISF
- ISF demonstrates a LTV current to phase system



Relationship of ISF and Phase Noise



$$\phi(t) = \int_{-\infty}^{\infty} h_{\phi}(t, \tau) i(\tau) d\tau = \int_{-\infty}^t \frac{\Gamma(\omega_0 \tau)}{q_{max}} i(\tau) d\tau$$

$$\phi(t) = \frac{1}{q_{max}} \left[c_0 \int_{-\infty}^t i(\tau) d\tau + \sum_{n=1}^{\infty} c_n \int_{-\infty}^t i(\tau) \cos(n\omega_0 \tau) d\tau \right]$$

Two step process to get phase noise

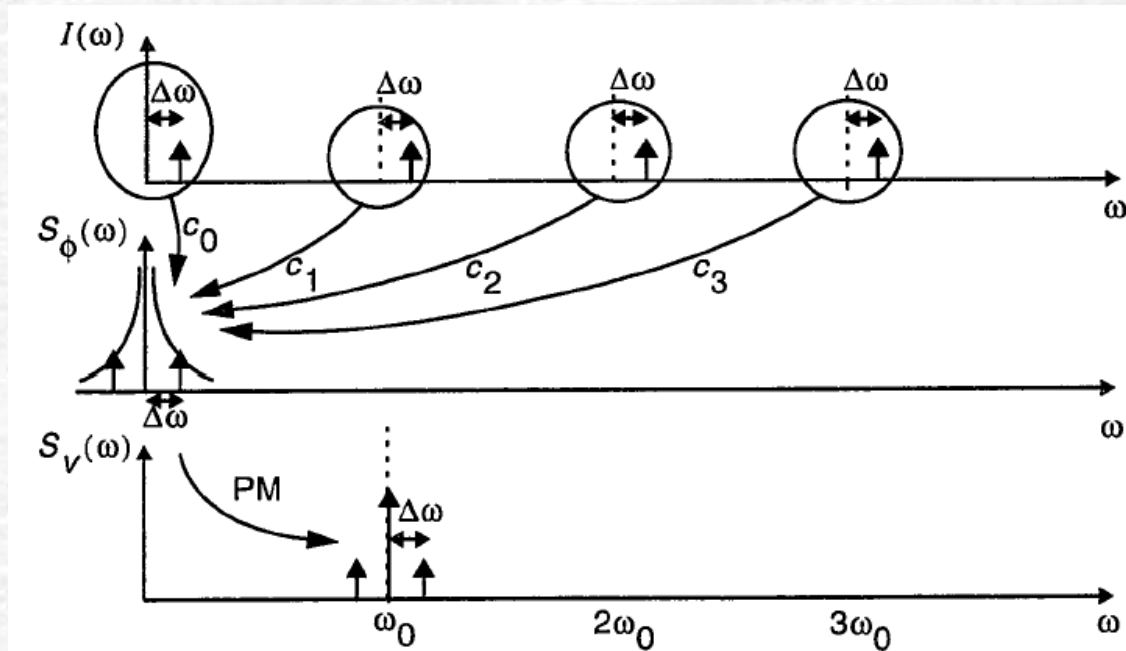
- Linear Current to Phase conversion (ISF)
- Nonlinear Phase to Voltage conversion

Sinusoidal Noise Source

$$i(t) = I_0 \cos(\Delta\omega t)$$

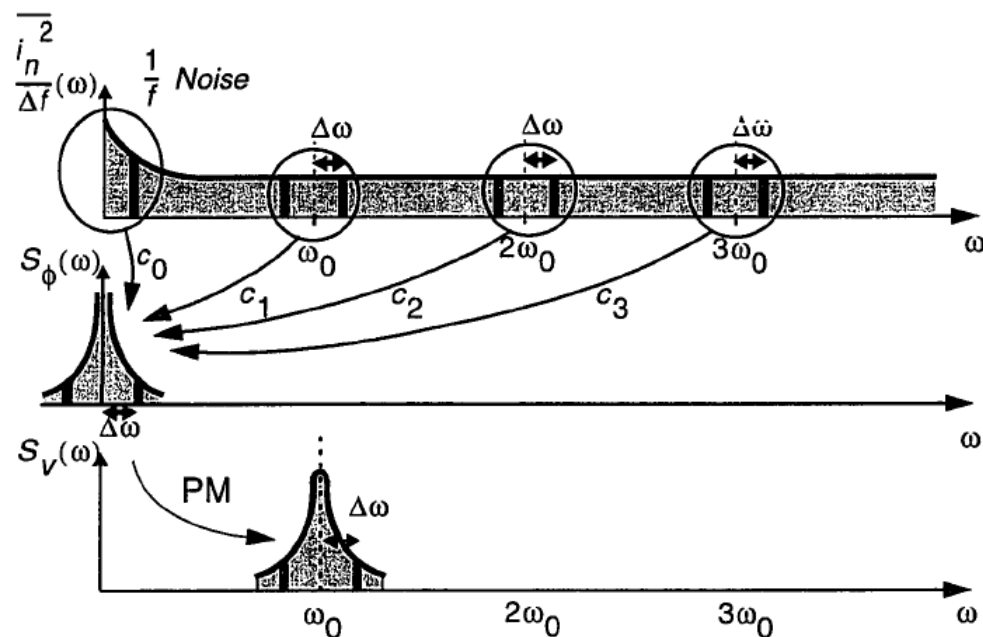
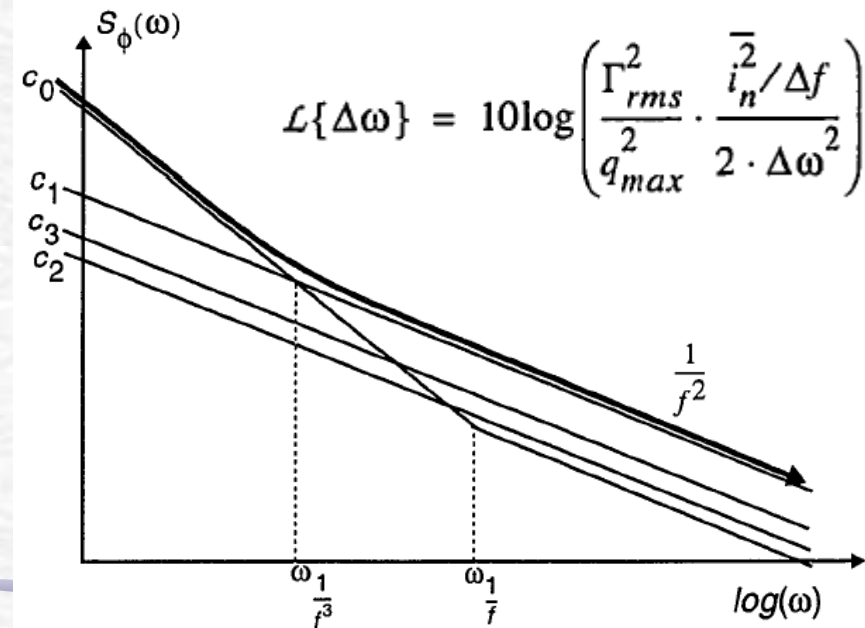
- Current at $n\omega_0 + \Delta\omega$ will result in two equal sideband at $\pm\Delta\omega$ $S_\phi(\omega)$, $\Delta\omega \ll \omega_0$
- $S_v(\omega)$ is nonlinear transfer function with $\phi(t)$ as the input

$$\phi(t) \approx \frac{I_0 c_0}{q_{max}} \int_{-\infty}^t \cos(\Delta\omega \tau) d\tau = \frac{I_0 c_0 \sin(\Delta\omega t)}{q_{max} \Delta\omega}$$



General Noise Source

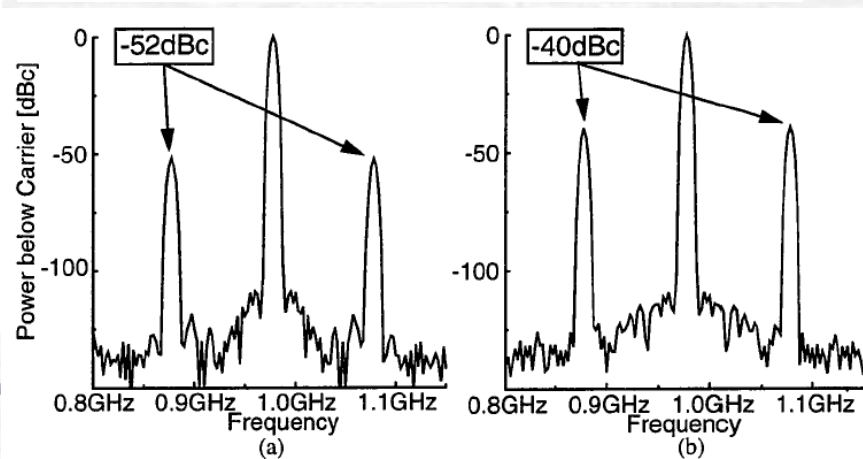
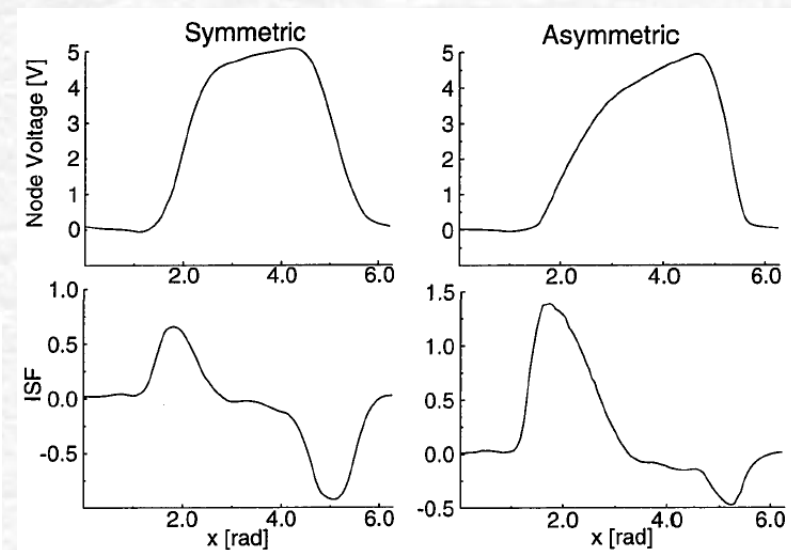
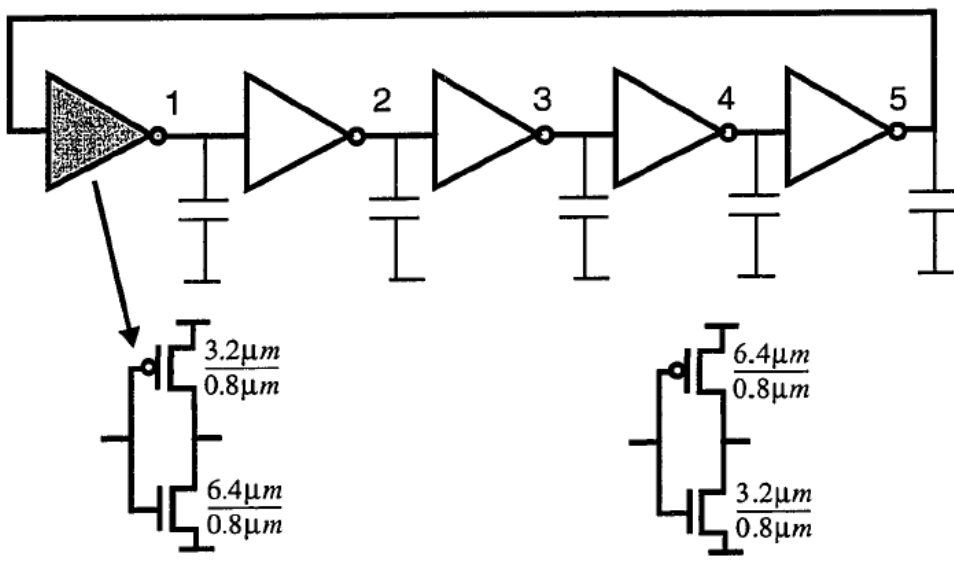
- Device's flicker noise is scaled by c_0 and become $1/f^3$ region in the phase noise spectrum



- Important to minimize the DC component of the ISF to lower $1/f^3$ corner
- Lower RMS value of ISF to lower phase noise

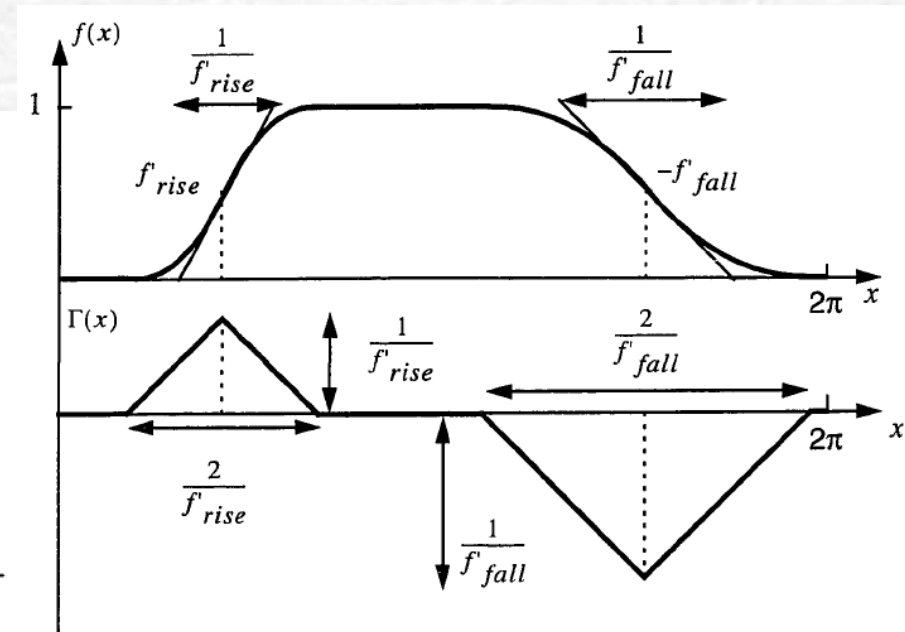
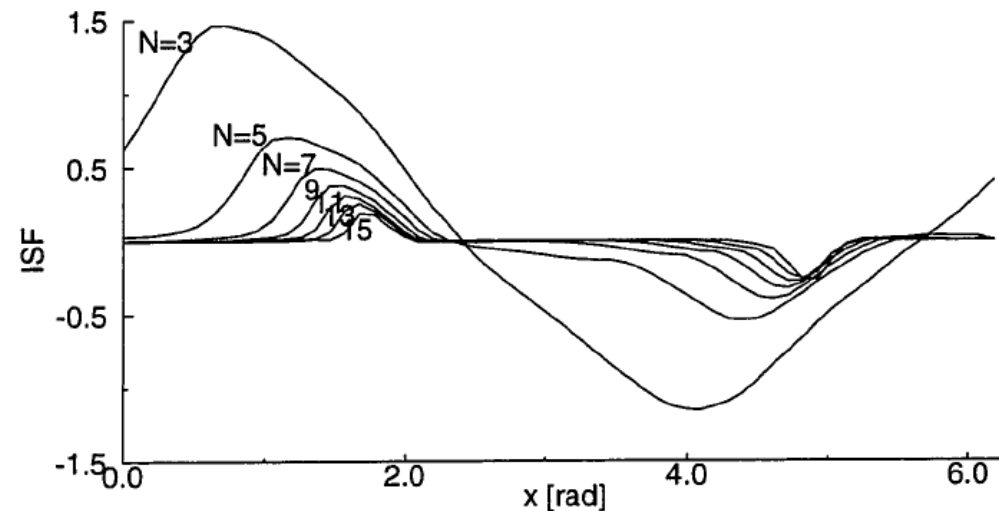
Minimizing Low Frequency Noise Contribution

- DC value of the ISF relates to the symmetry of the waveform



Estimation of ISF

- Estimate using triangular function
- Peak and width of ISF inversely related to slope of transition
- $A = f_{\text{rise}}/f_{\text{fall}}$



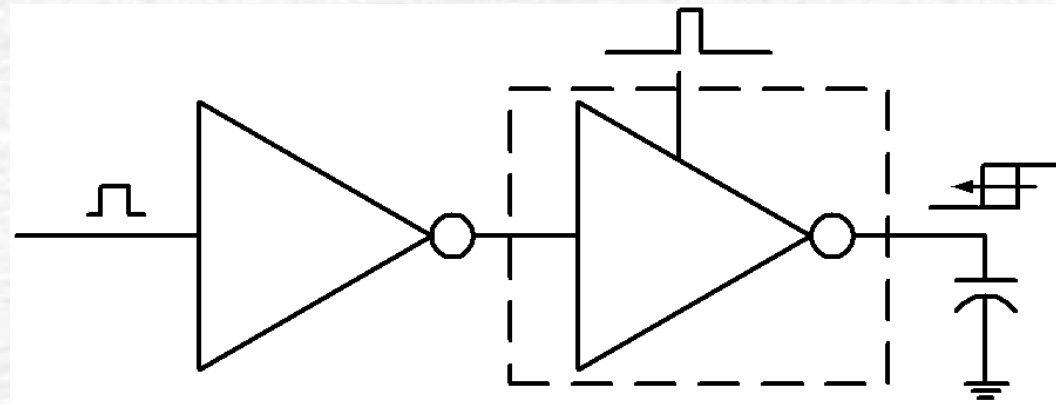
$$\Gamma_{\text{rms}}^2 = \frac{1}{\pi} \left[\int_0^{1/f'_{\text{rise}}} x^2 dx + \int_0^{1/f'_{\text{fall}}} x^2 dx \right] = \frac{1}{3\pi} \left(\frac{1}{f'_{\text{rise}}} \right)^3 (1 + A^3)$$

$$\Gamma_{\text{dc}} = \frac{2\pi}{\eta^2} \frac{1}{N^2} \left(\frac{1-A}{1+A} \right)$$

Measuring ISF for V_{DD} Noise

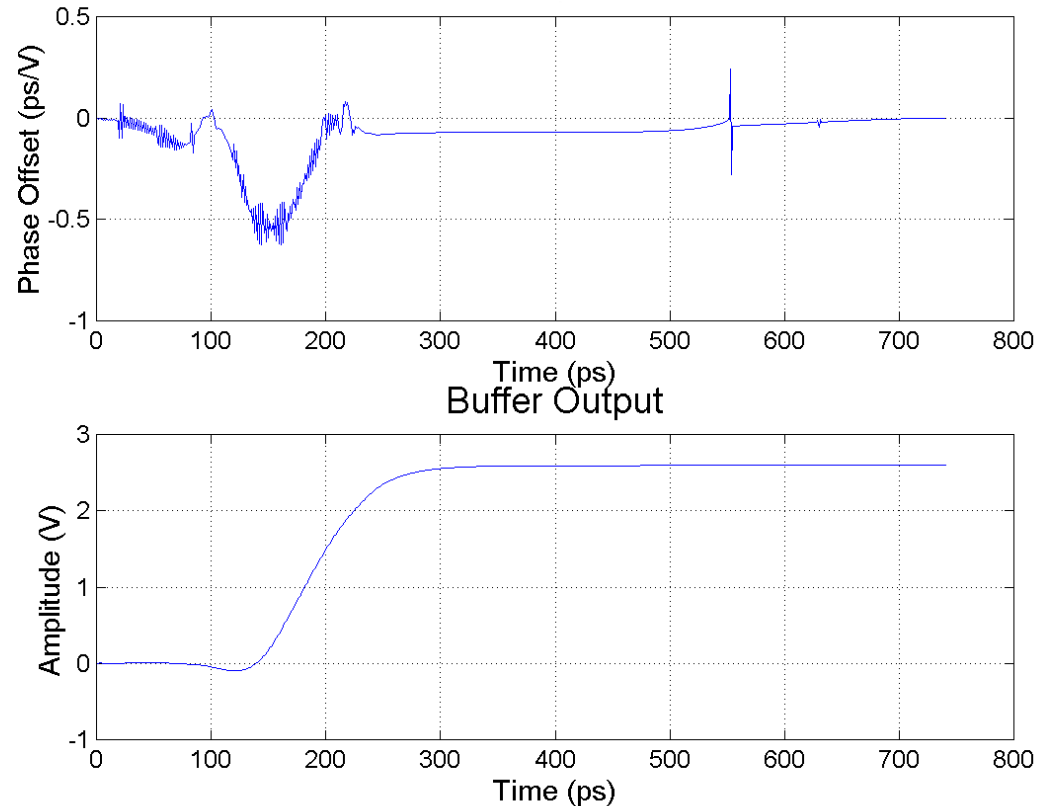
Clock Buffer Characterization

- Fix input clock transition time
- Apply impulse function noise source to V_{DD}
- Measure $\frac{1}{2}V_{DD}$ crossing of output
- Sweep transition time of V_{DD} noise
- Compare results with noiseless case to get phase change



Measuring ISF for V_{DD} Noise

- V_{DD} noise simulation
- Agrees with earlier analysis on shape of ISF
- Maximum occurs at the transition



Conclusions

- ✓ Phase noise and timing jitter are related
- ✓ RMS and DC value of ISF directly relates to the shape of the phase noise spectrum
- ✓ Design goal: symmetry is important for minimizing phase noise
- ✓ The ISF can be used to calculate the phase jitter due to supply noise